

# P79 Low Distortion Signal Generation for ADC Linearity Test

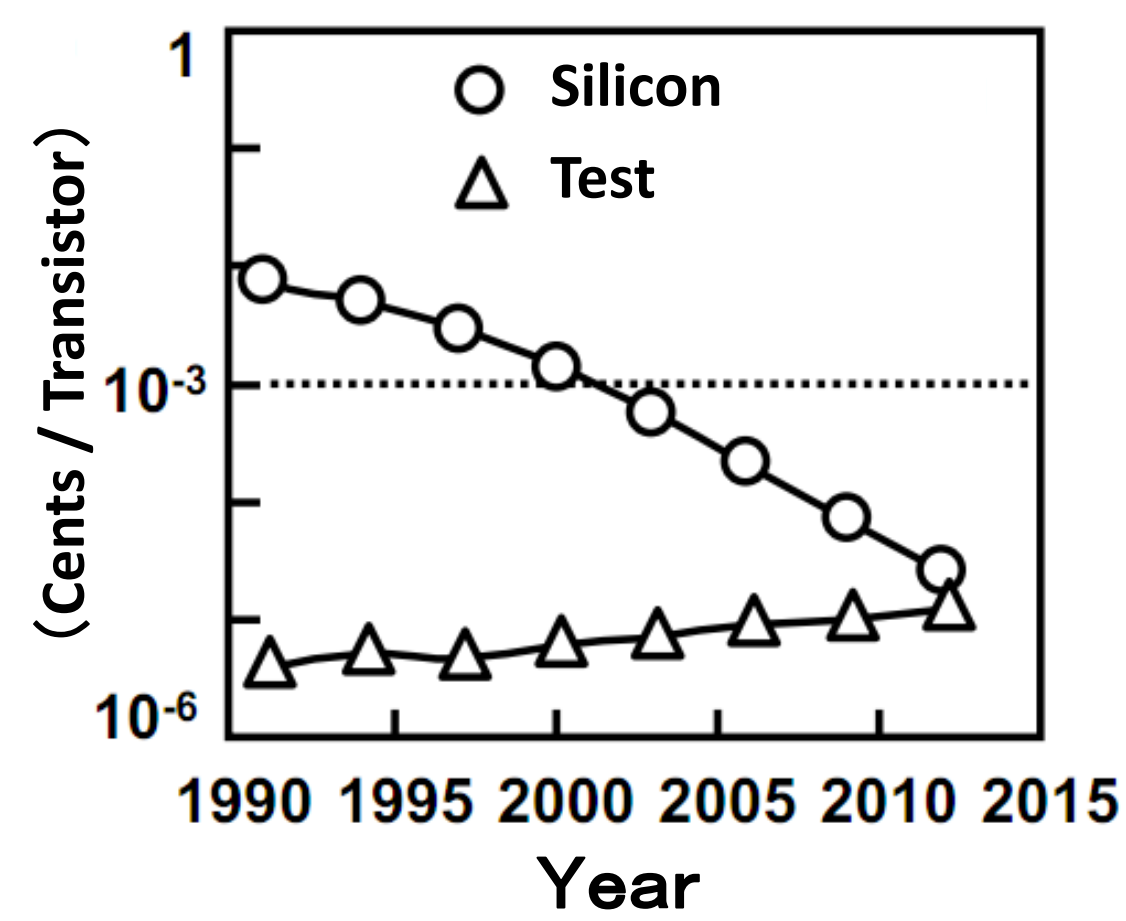
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## Industrial Background

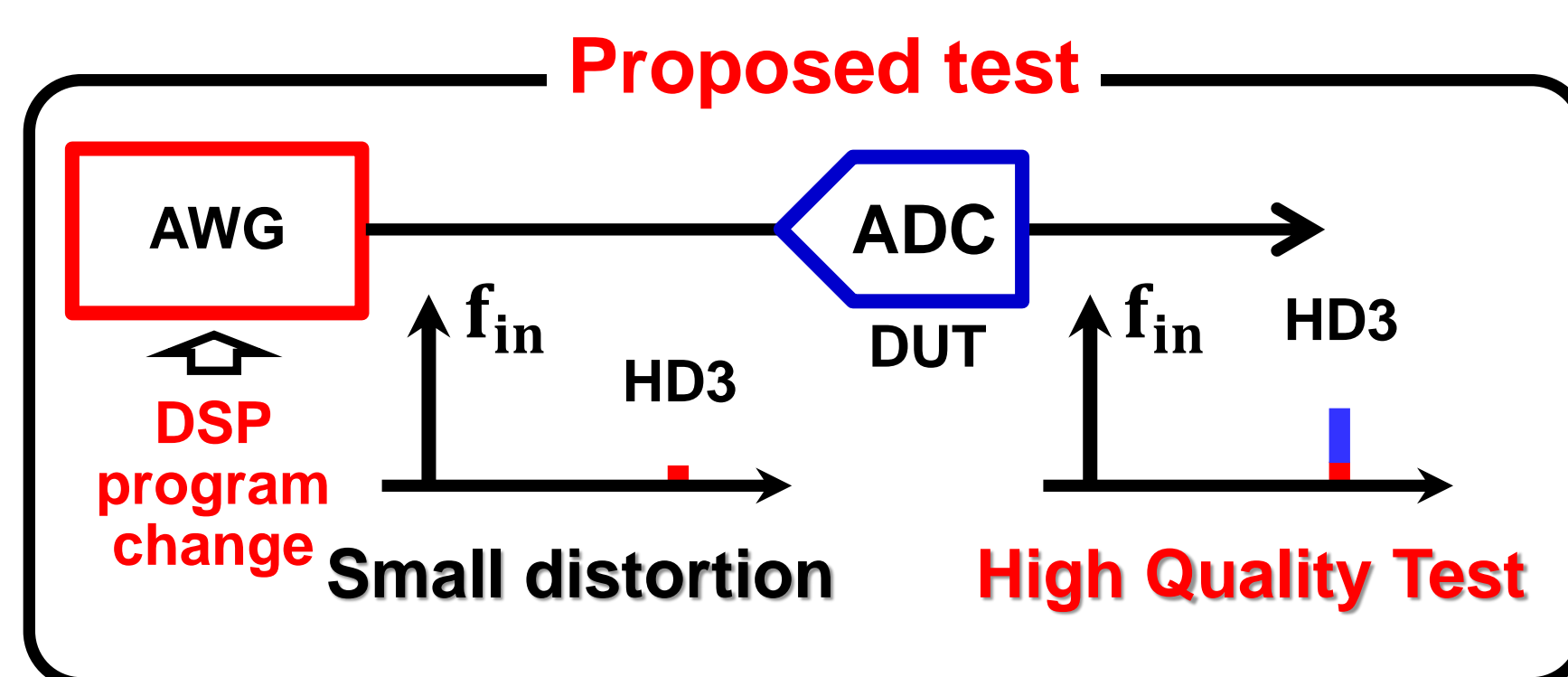
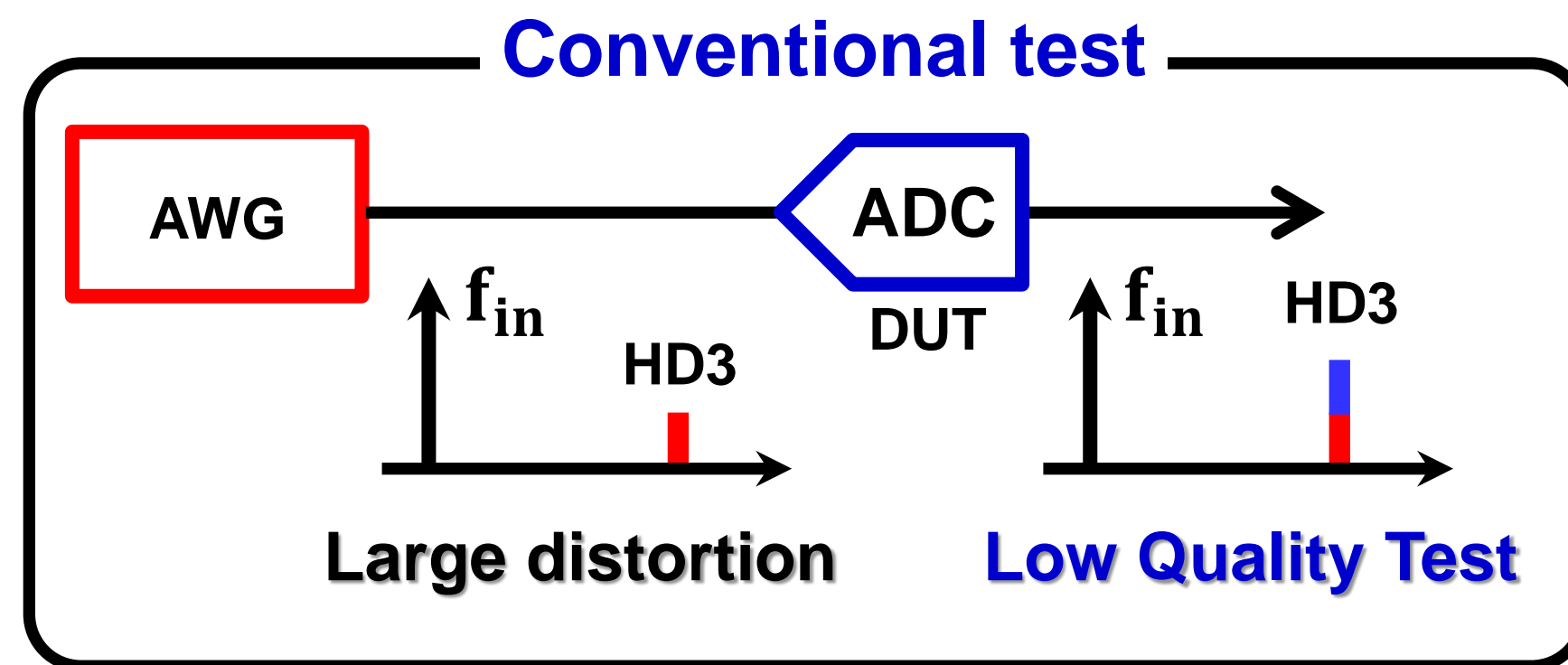
- Need for ADC **low-cost** test
- Need for ADC **high-quality** test



Silicon Cost : Reduce  
Test Cost : Increase

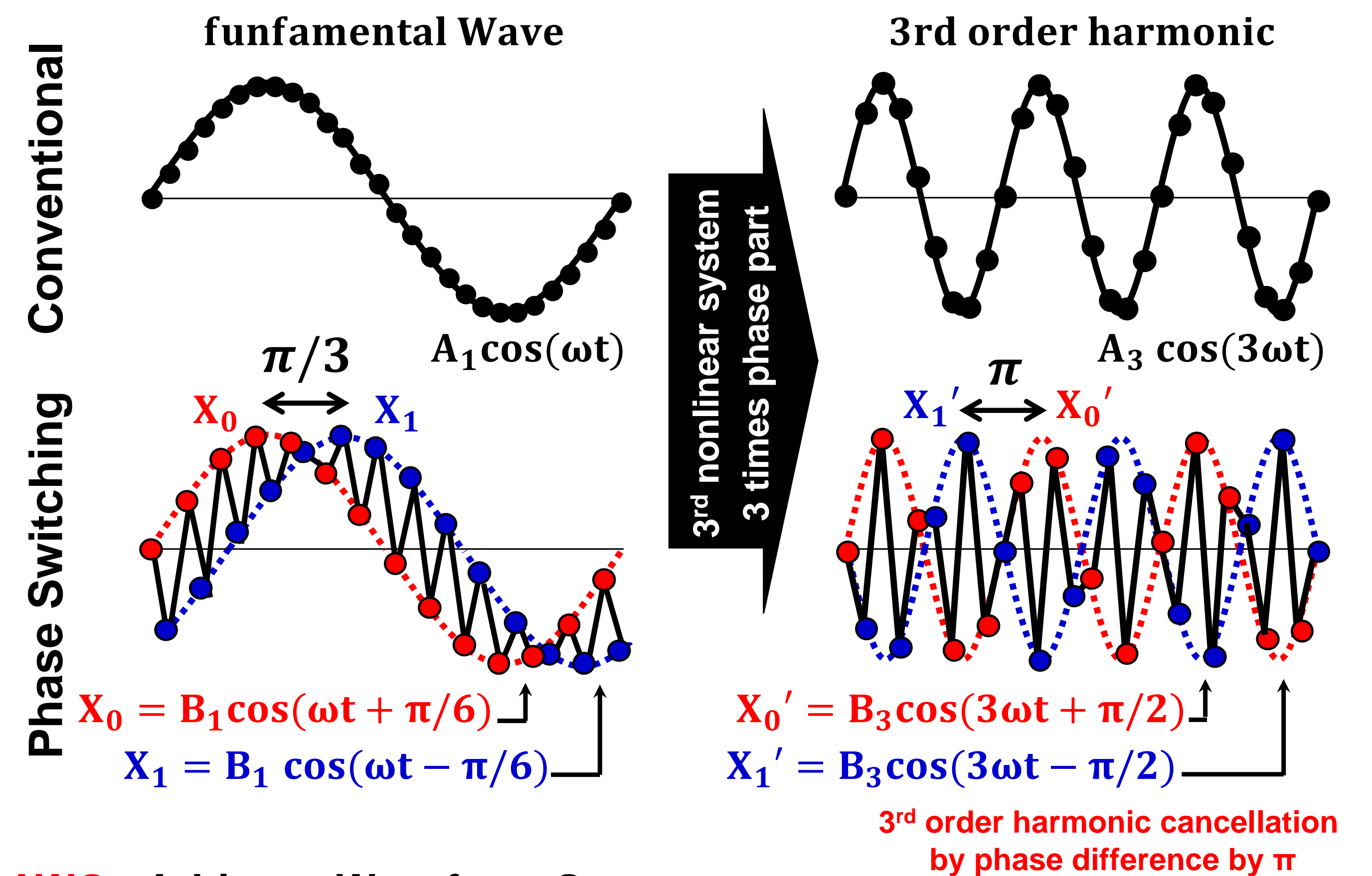
## Research Goal

High Quality ADC test with a low cost AWG



Proposed test can realize high quality test with the conventional AWG

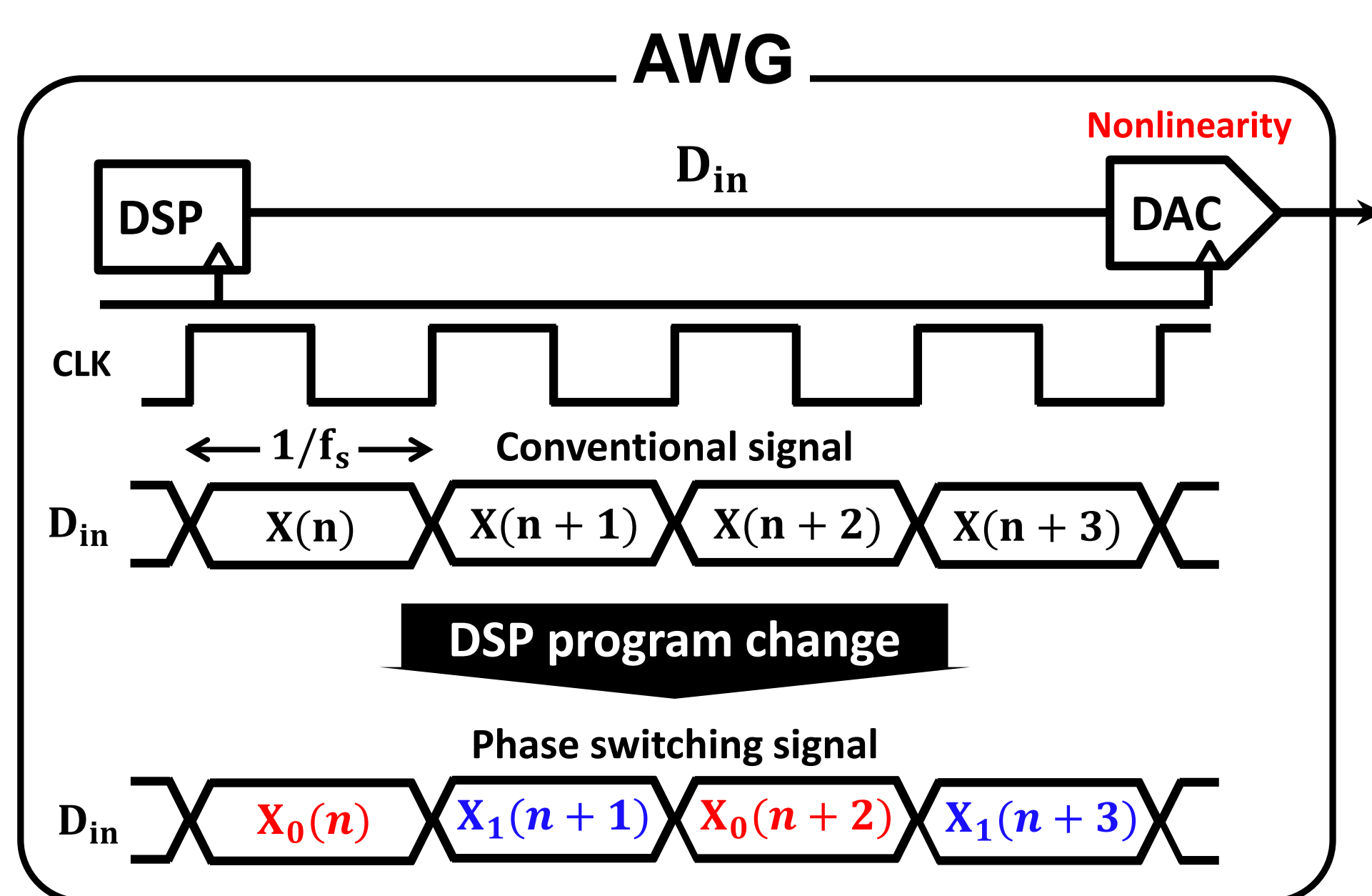
## Principle of distortion signal cancellation



AWG : Arbitrary Waveform Generator

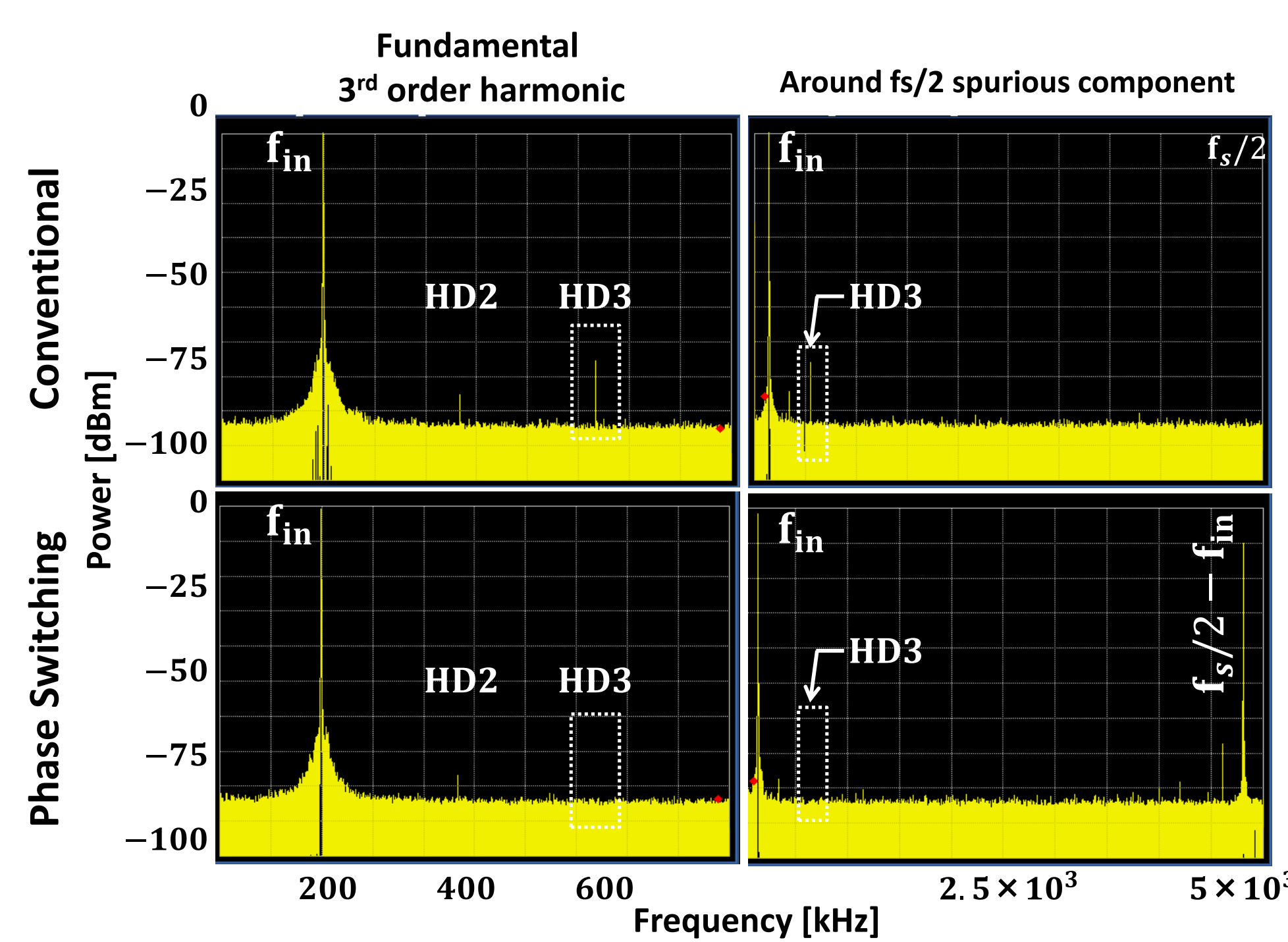
Introduction

## Test signal generation with an AWG



Conventional signal  $X(n) = A \cos(2\pi f_{in} n T_s)$   
 Phase Switching signal  
 $X_0(n) = B \cos(2\pi f_{in} n T_s + \pi/6)$   
 $X_1(n) = B \cos(2\pi f_{in} n T_s - \pi/6)$   
 Here,  $B = 1.15A$

## Conventional and Phase switching signals



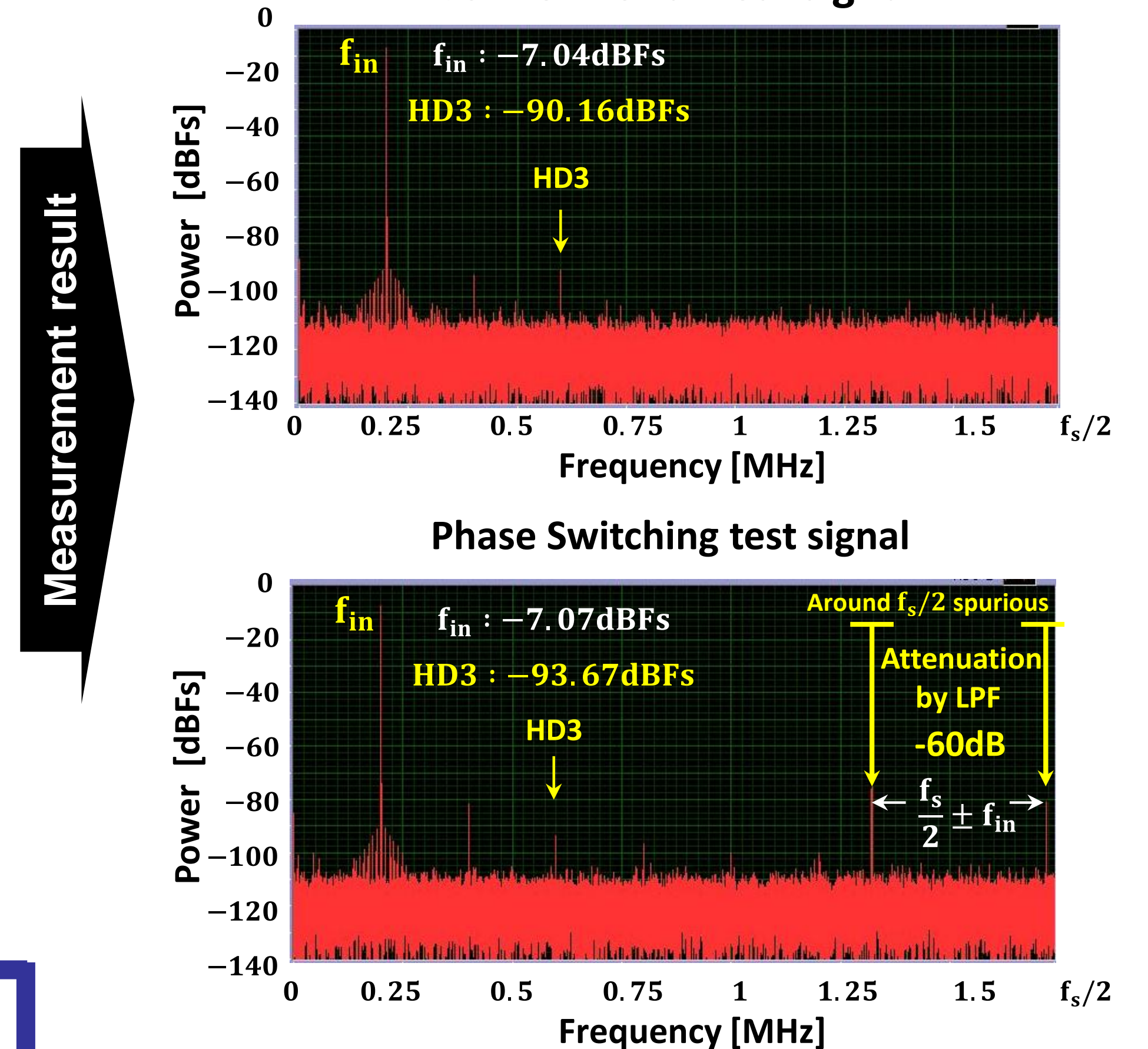
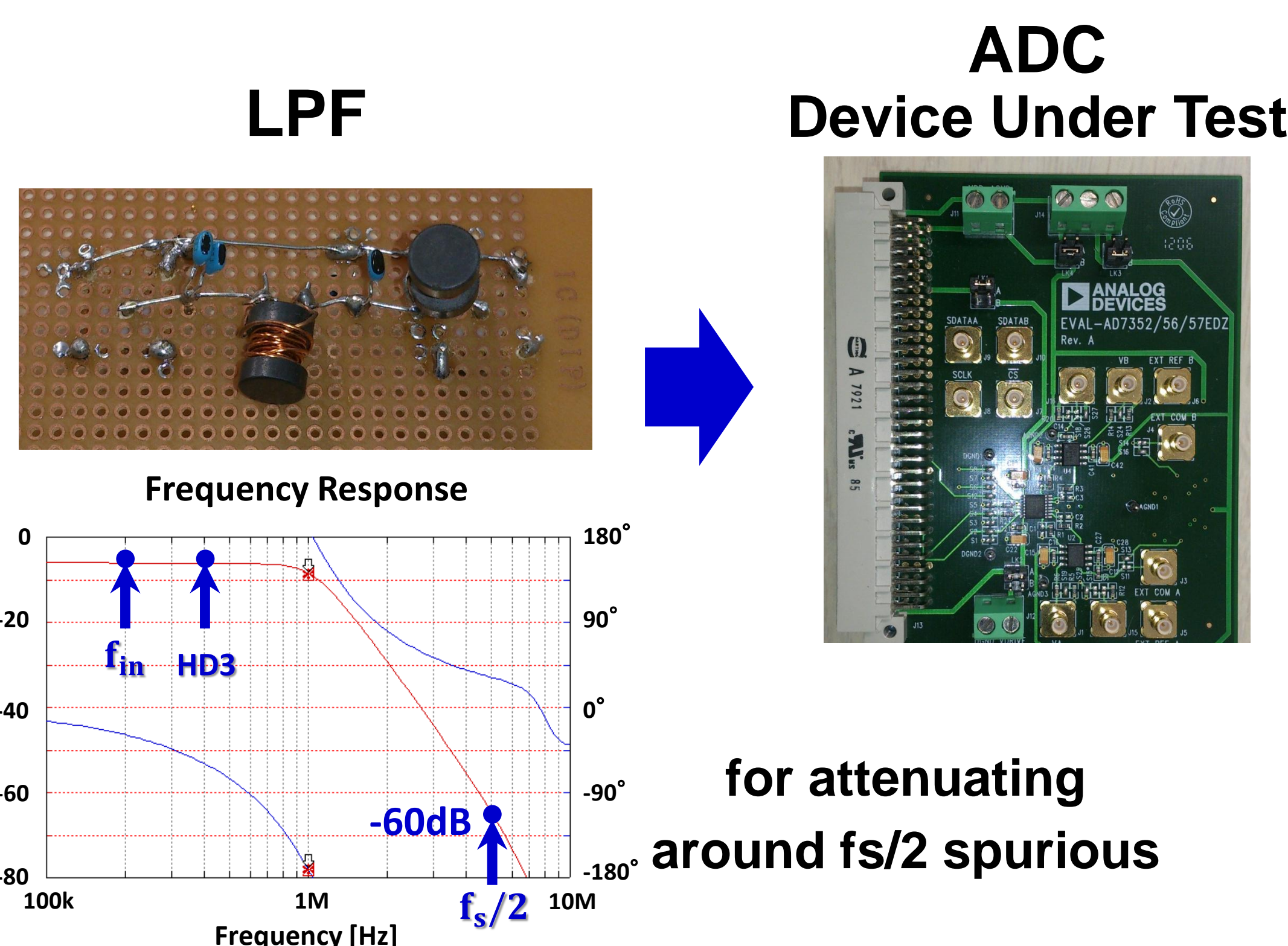
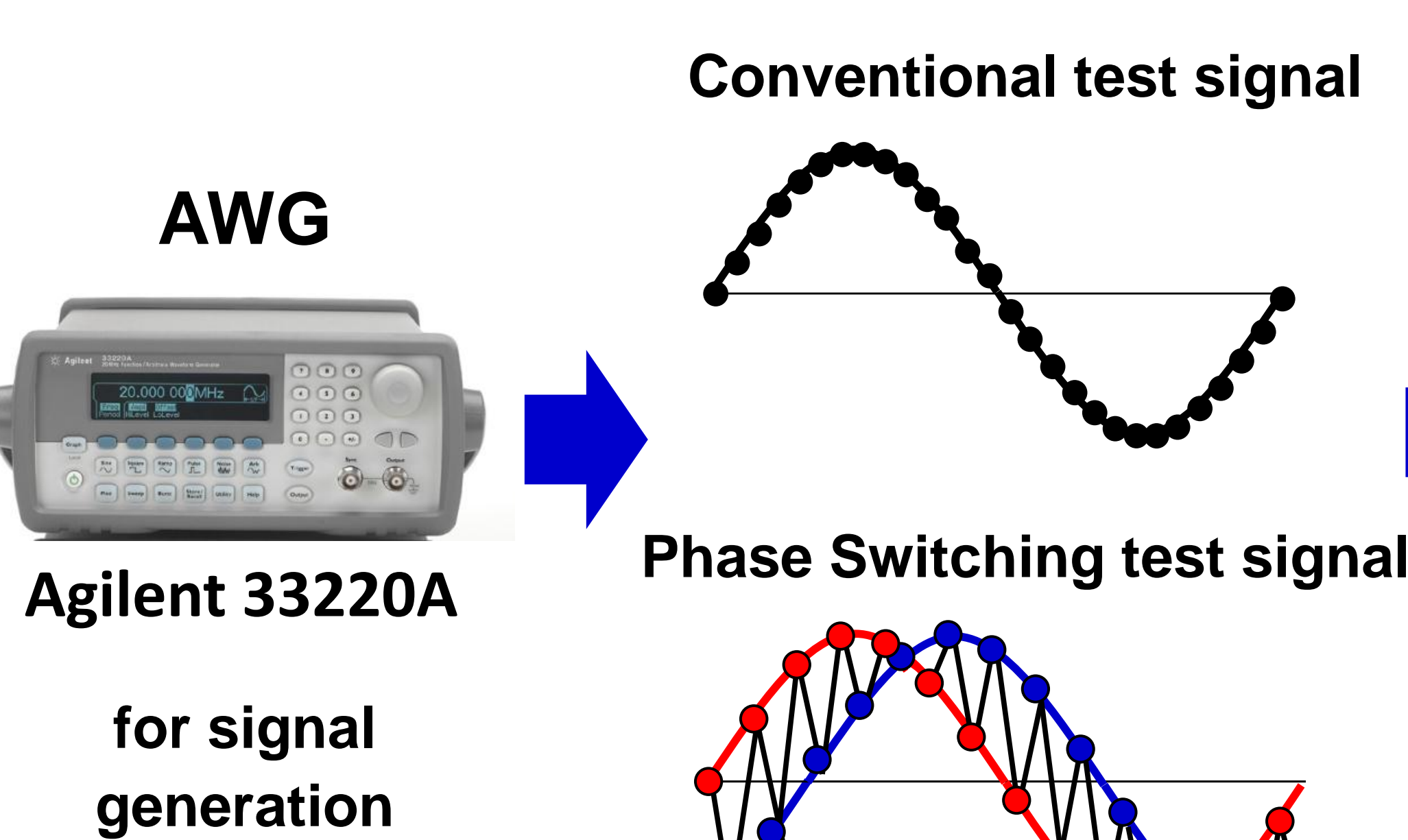
Comparing conventional and phase switching

3rd order harmonic disappear

## Comparison of conventional and phase switching signals

	Undesired Signal	Undesired signal reduction by a filter
Conventional	$3f_{in}$ Around Fundamental	Hard
Phase Switching	$f_s/2 - f_{in}$ Around $f_s/2$ spurious	Easy

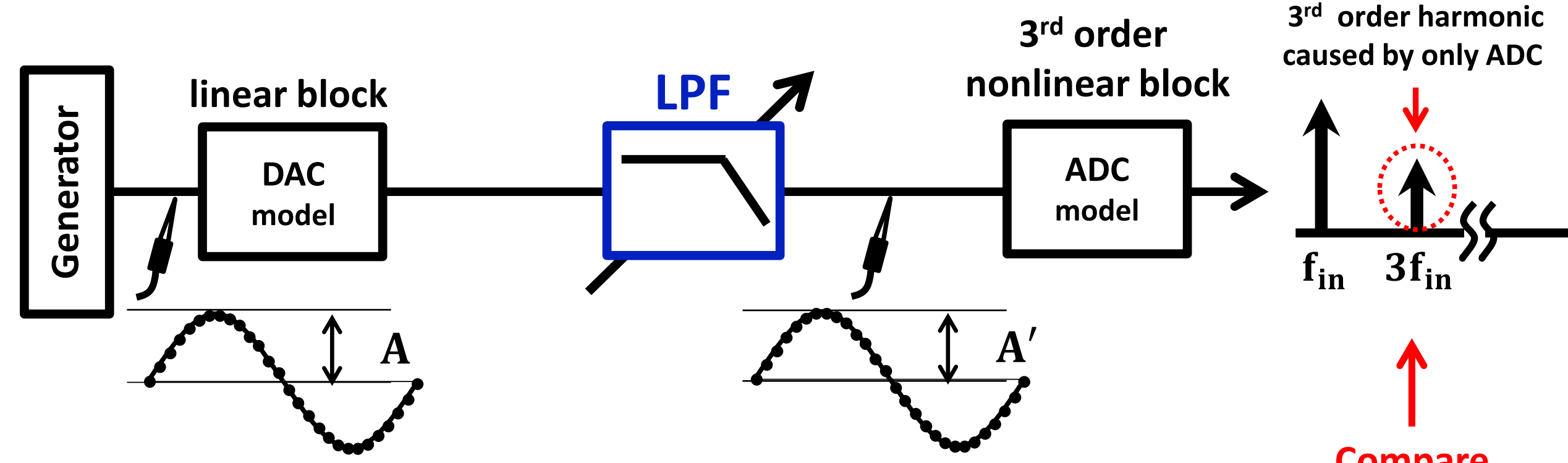
Low distortion sine wave generation



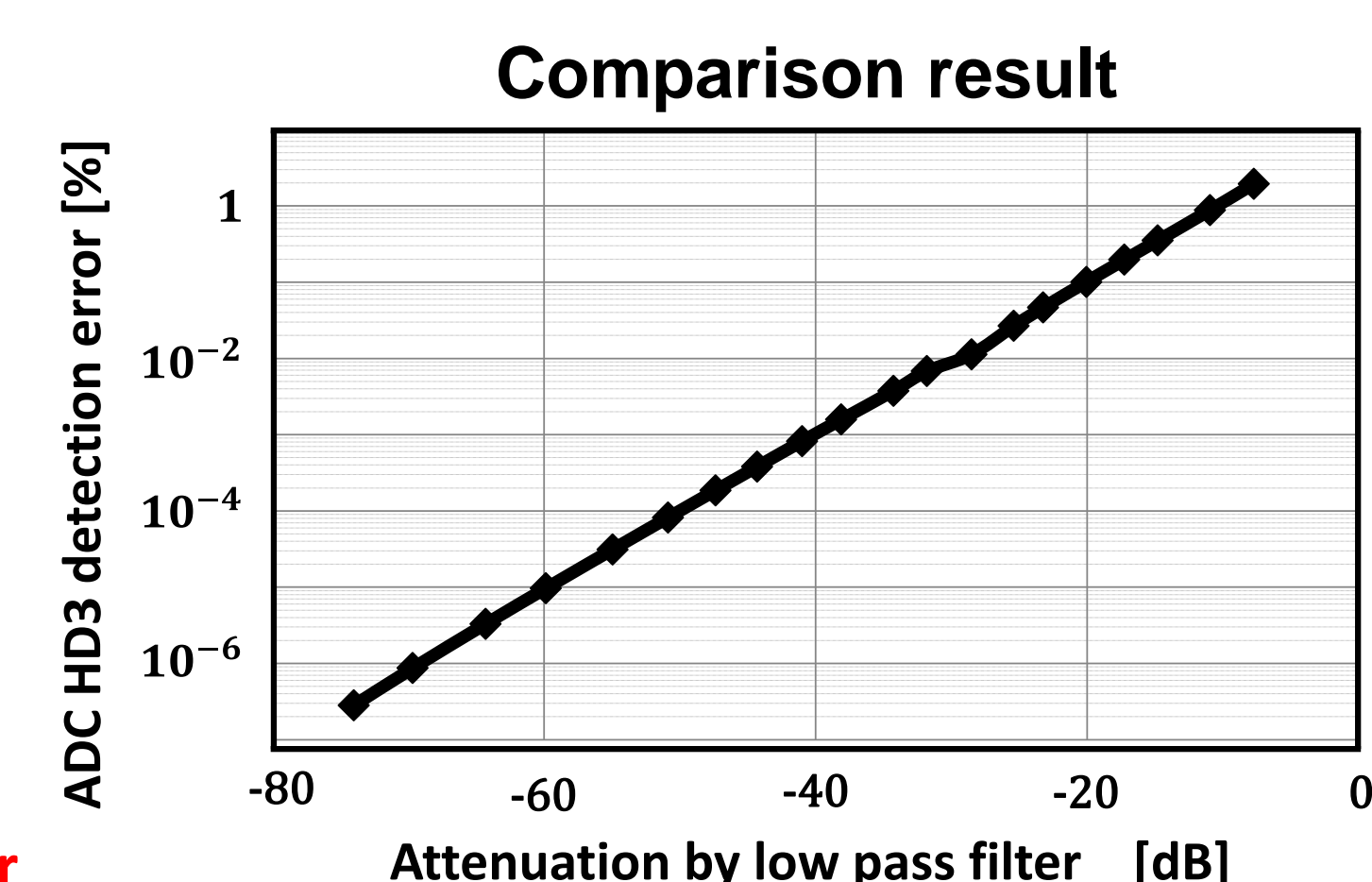
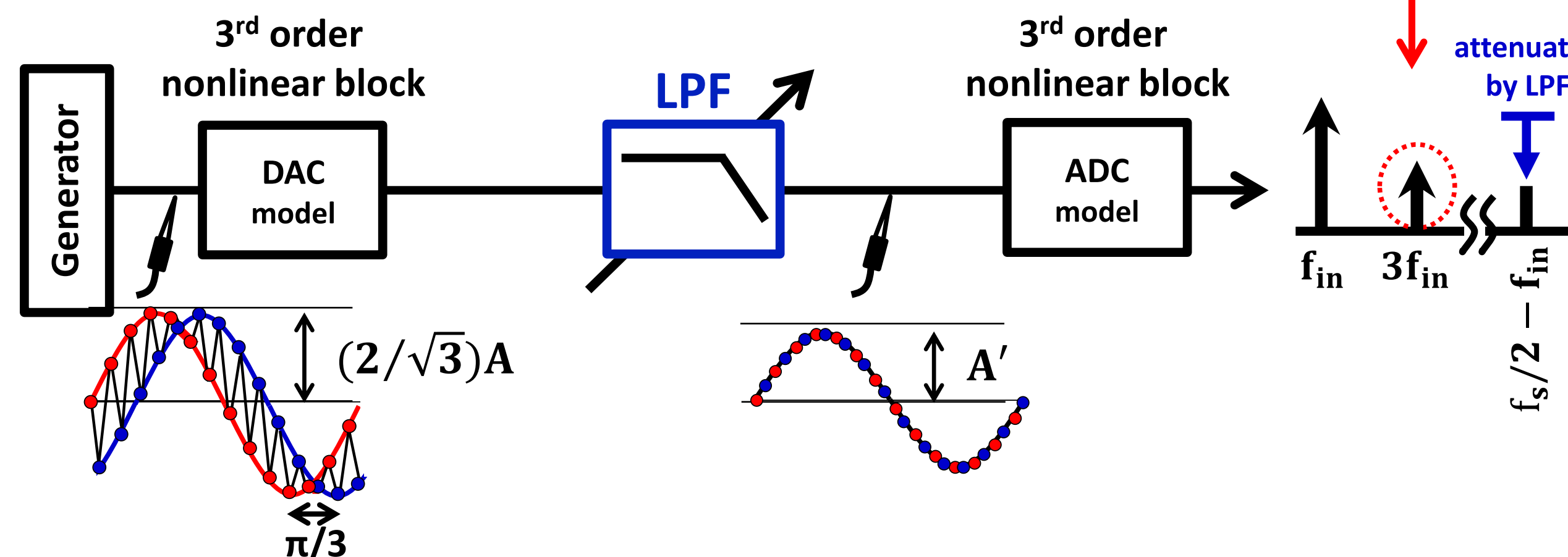
ADC dynamic performance measurement

around fs/2 spurious attenuation

## Ideal test system with Conventional signal



## Real test system with phase switching signal



Attenuation	HD3 detection error
$f_s/2 - f_{in}$ attenuation	0.1 %
-20dB	0.01 %
-30dB	0.001 %

Conclusion

- ADC linearity test with AWG
- Phase switching signal & simple LPF realize high quality ADC test
- Only AWG program change

conventional	Phase Switching
-90.2dB	-93.7dB
Including DAC + ADC HD3	mainly Including ADC HD3
Low quality test	High quality test